

# IRGI4060DPbF

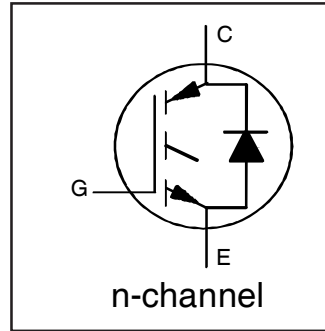
## INSULATED GATE BIPOLAR TRANSISTOR WITH ULTRAFAST SOFT RECOVERY DIODE

### Features

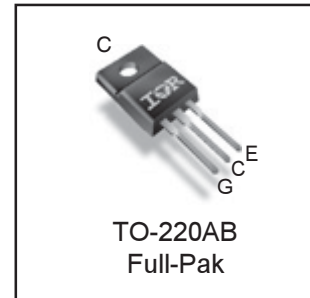
- Low  $V_{CE(on)}$  Trench IGBT Technology
- Low Switching Losses
- 5 $\mu$ s SCSOA
- Square RBSOA
- 100% of The Parts Tested for  $I_{LM}$  ①
- Positive  $V_{CE(on)}$  Temperature Coefficient.
- Ultra Fast Soft Recovery Co-pak Diode
- Tighter Distribution of Parameters
- Lead-Free Package

### Benefits

- High Efficiency in a Wide Range of Applications
- Suitable for a Wide Range of Switching Frequencies due to Low  $V_{CE(ON)}$  and Low Switching Losses
- Rugged Transient Performance for Increased Reliability
- Excellent Current Sharing in Parallel Operation
- Low EMI



$V_{CES} = 600V$
$I_C = 7.5A, T_C = 100^\circ C$
$t_{sc} > 5\mu s, T_{jmax} = 150^\circ C$
$V_{CE(on) typ.} = 1.50V$



<b>G</b>	<b>C</b>	<b>E</b>
Gate	Collector	Emitter

### Absolute Maximum Ratings

	Parameter	Max.	Units
$V_{CES}$	Collector-to-Emitter Breakdown Voltage	600	V
$I_C @ T_C = 25^\circ C$	Continuous Collector Current	14	A
$I_C @ T_C = 100^\circ C$	Continuous Collector Current	7.5	
$I_{CM}$	Pulse Collector Current, $V_{GE}=15V$	23	
$I_{LM}$	Clamped Inductive Load Current, $V_{GE}=20V$ ①	30	
$I_F @ T_C=25^\circ C$	Diode Continuous Forward Current	14	
$I_F @ T_C=100^\circ C$	Diode Continuous Forward Current	7.5	
$I_{FM}$	Diode Maximum Forward Current ②	30	
$V_{GE}$	Continuous Gate-to-Emitter Voltage	$\pm 20$	V
	Transient Gate-to-Emitter Voltage	$\pm 30$	
$P_D @ T_C = 25^\circ C$	Maximum Power Dissipation	37	W
$P_D @ T_C = 100^\circ C$	Maximum Power Dissipation	15	
$T_J$ $T_{STG}$	Operating Junction and Storage Temperature Range	-55 to + 150	$^\circ C$
	Soldering Temperature, for 10 seconds	300 (0.063 in. (1.6mm) from case)	
	Mounting Torque, 6-32 or M3 Screw	10 lbf-in (1.1 N-m)	

### Thermal Resistance

	Parameter	Min.	Typ.	Max.	Units
$R_{\theta JC}$	Junction-to-Case - IGBT ③	—	—	3.40	$^\circ C/W$
$R_{\theta JC}$	Junction-to-Case - Diode ③	—	—	6.10	
$R_{\theta CS}$	Case-to-Sink, flat, greased surface	—	0.5	—	
$R_{\theta JA}$	Junction-to-Ambient, typical socket mount ③	—	—	65	
Wt	Weight	—	2.0	—	g

**Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)**

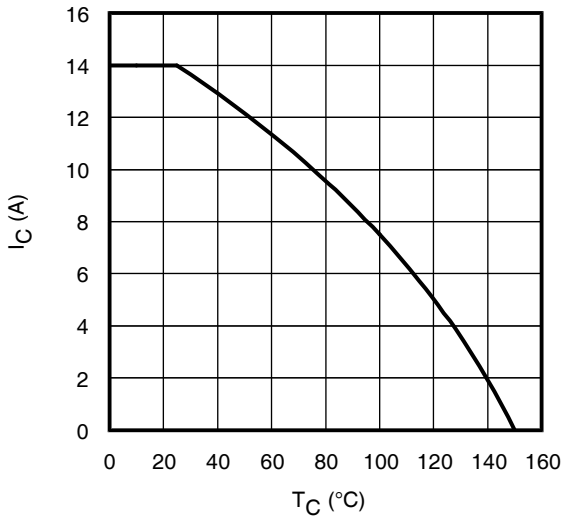
	Parameter	Min.	Typ.	Max.	Units	Conditions
V <sub>(BR)CES</sub>	Collector-to-Emitter Breakdown Voltage	600	—	—	V	V <sub>GE</sub> = 0V, I <sub>C</sub> = 100 μA ④
ΔV <sub>(BR)CES</sub> /ΔT <sub>J</sub>	Temperature Coeff. of Breakdown Voltage	—	0.66	—	V/°C	V <sub>GE</sub> = 0V, I <sub>C</sub> = 250 μA ( -55 -150 °C ) ④
V <sub>CE(on)</sub>	Collector-to-Emitter Saturation Voltage	—	1.50	1.72		I <sub>C</sub> = 7.5A, V <sub>GE</sub> = 15V, T <sub>J</sub> = 25°C
		—	1.75	—	V	I <sub>C</sub> = 7.5A, V <sub>GE</sub> = 15V, T <sub>J</sub> = 125°C
		—	1.81	—		I <sub>C</sub> = 7.5A, V <sub>GE</sub> = 15V, T <sub>J</sub> = 150°C
V <sub>GE(th)</sub>	Gate Threshold Voltage	4.0	—	6.5	V	V <sub>CE</sub> = V <sub>GE</sub> , I <sub>C</sub> = 250 μA
ΔV <sub>GE(th)</sub> /ΔT <sub>J</sub>	Threshold Voltage temp. coefficient	—	-12	—	mV/°C	V <sub>CE</sub> = V <sub>GE</sub> , I <sub>C</sub> = 1.0mA ( -55 -150 °C )
g <sub>fe</sub>	Forward Transconductance	—	5	—	S	V <sub>CE</sub> = 50V, I <sub>C</sub> = 7.5A, PW = 80μs
I <sub>CES</sub>	Collector-to-Emitter Leakage Current	—	1.0	25	μA	V <sub>GE</sub> = 0V, V <sub>CE</sub> = 600V
		—	400	—	μA	V <sub>GE</sub> = 0V, V <sub>CE</sub> = 600V, T <sub>J</sub> = 150°C
V <sub>FM</sub>	Diode Forward Voltage Drop	—	2.18	3.00	V	I <sub>F</sub> = 7.5A
		—	1.60	—		I <sub>F</sub> = 7.5A, T <sub>J</sub> = 150°C
I <sub>GES</sub>	Gate-to-Emitter Leakage Current	—	—	±100	nA	V <sub>GE</sub> = ± 20 V

**Switching Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)**

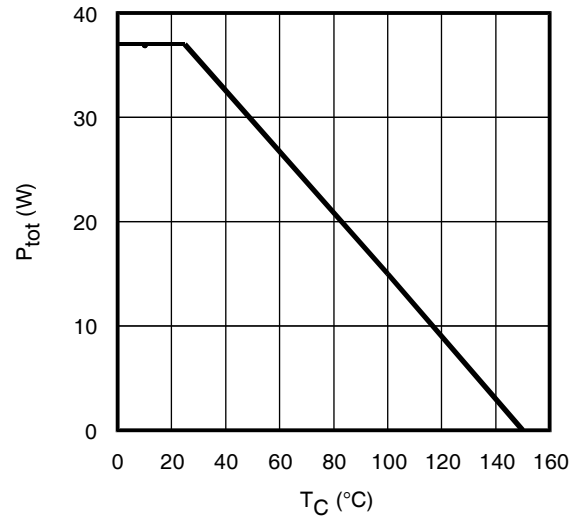
	Parameter	Min.	Typ.	Max.	Units	Conditions
Q <sub>g</sub>	Total Gate Charge (turn-on)	—	19	29	nC	I <sub>C</sub> = 7.5A V <sub>CC</sub> = 400V V <sub>GE</sub> = 15V
Q <sub>ge</sub>	Gate-to-Emitter Charge (turn-on)	—	4.3	6		
Q <sub>gc</sub>	Gate-to-Collector Charge (turn-on)	—	8.3	12		
E <sub>on</sub>	Turn-On Switching Loss	—	47	89	μJ	I <sub>C</sub> = 7.5A, V <sub>CC</sub> = 400V, V <sub>GE</sub> = 15V R <sub>G</sub> = 47Ω, L = 1mH, L <sub>S</sub> = 150nH, T <sub>J</sub> = 25°C Energy losses include tail and diode reverse recovery
E <sub>off</sub>	Turn-Off Switching Loss	—	141	248		
E <sub>total</sub>	Total Switching Loss	—	188	337		
t <sub>d(on)</sub>	Turn-On delay time	—	29	38	ns	I <sub>C</sub> = 7.5A, V <sub>CC</sub> = 400V R <sub>G</sub> = 47Ω, L = 1mH, L <sub>S</sub> = 150nH T <sub>J</sub> = 25°C
t <sub>r</sub>	Rise time	—	16	25		
t <sub>d(off)</sub>	Turn-Off delay time	—	101	112		
t <sub>f</sub>	Fall time	—	28	37		
E <sub>on</sub>	Turn-On Switching Loss	—	107	—	μJ	I <sub>C</sub> = 7.5A, V <sub>CC</sub> = 400V, V <sub>GE</sub> = 15V R <sub>G</sub> = 47Ω, L = 1mH, L <sub>S</sub> = 150nH, T <sub>J</sub> = 150°C Energy losses include tail and diode reverse recovery
E <sub>off</sub>	Turn-Off Switching Loss	—	196	—		
E <sub>total</sub>	Total Switching Loss	—	304	—		
t <sub>d(on)</sub>	Turn-On delay time	—	28	—	ns	I <sub>C</sub> = 7.5A, V <sub>CC</sub> = 400V R <sub>G</sub> = 47Ω, L = 1mH, L <sub>S</sub> = 150nH T <sub>J</sub> = 150°C
t <sub>r</sub>	Rise time	—	17	—		
t <sub>d(off)</sub>	Turn-Off delay time	—	118	—		
t <sub>f</sub>	Fall time	—	53	—		
C <sub>ies</sub>	Input Capacitance	—	537	—	pF	V <sub>GE</sub> = 0V V <sub>CC</sub> = 30V f = 1Mhz
C <sub>oes</sub>	Output Capacitance	—	47	—		
C <sub>res</sub>	Reverse Transfer Capacitance	—	16	—		
RBSOA	Reverse Bias Safe Operating Area	FULL SQUARE				T <sub>J</sub> = 150°C, I <sub>C</sub> = 30A V <sub>CC</sub> = 480V, V <sub>p</sub> = 600V R <sub>G</sub> = 47Ω, V <sub>GE</sub> = +20V to 0V
SCSOA	Short Circuit Safe Operating Area	5	—	—	μs	V <sub>CC</sub> = 400V, V <sub>p</sub> = 600V R <sub>G</sub> = 47Ω, V <sub>GE</sub> = +15V to 0V
E <sub>rec</sub>	Reverse recovery energy of the diode	—	102	—	μJ	T <sub>J</sub> = 150°C
t <sub>rr</sub>	Diode Reverse recovery time	—	73	—	ns	V <sub>CC</sub> = 400V, I <sub>F</sub> = 7.5A
I <sub>rr</sub>	Peak Reverse Recovery Current	—	11	—	A	V <sub>GE</sub> = 15V, R <sub>G</sub> = 47Ω, L = 1mH, L <sub>S</sub> = 150nH

## Notes:

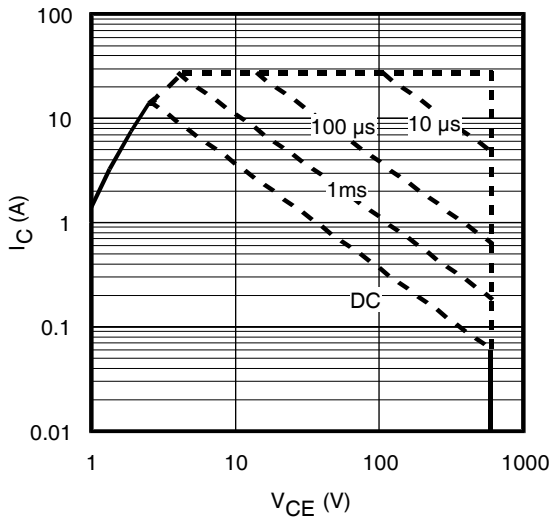
- ① V<sub>CC</sub> = 80% (V<sub>CES</sub>), V<sub>GE</sub> = 20V, L = 28 μH, R<sub>G</sub> = 47 Ω
- ② Pulse width limited by max. junction temperature.
- ③ R<sub>θ</sub> is measured at T<sub>J</sub> approximately 90°C
- ④ Refer to AN-1086 for guidelines for measuring V<sub>(BR)CES</sub> safely



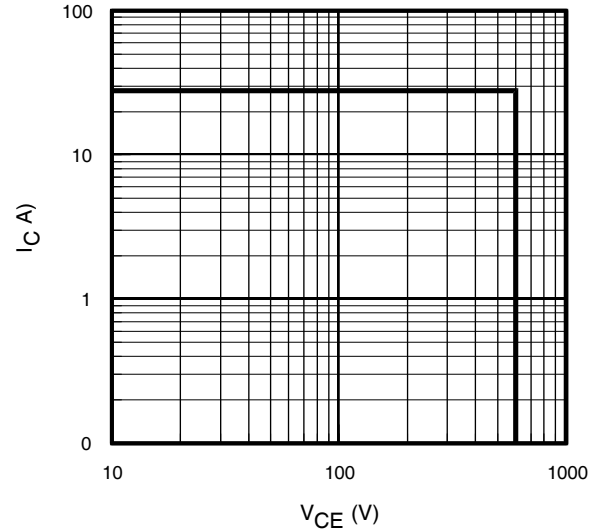
**Fig. 1** - Maximum DC Collector Current vs. Case Temperature



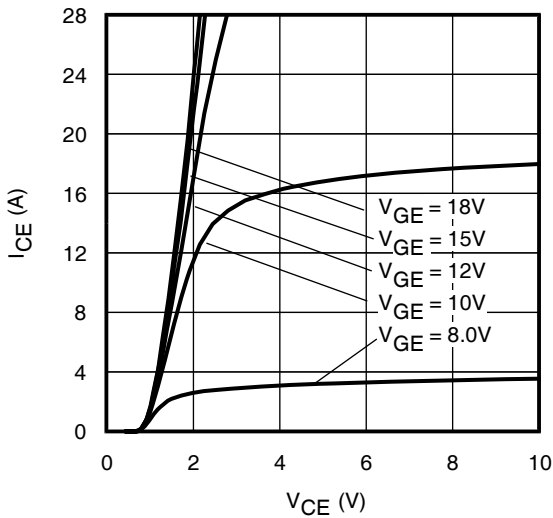
**Fig. 2** - Power Dissipation vs. Case Temperature



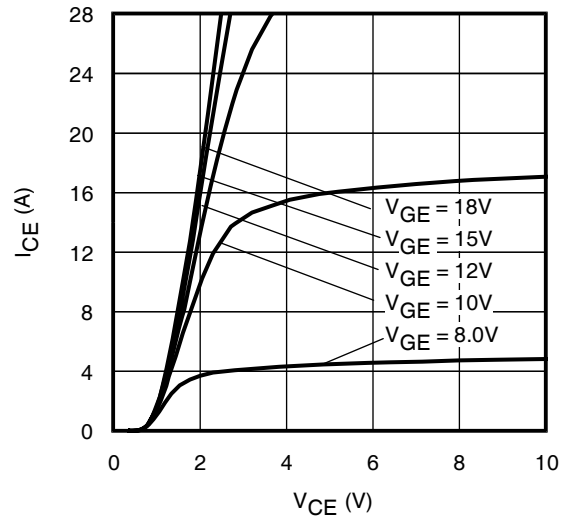
**Fig. 3** - Forward SOA,  
 $T_C = 25^\circ\text{C}$ ;  $T_J \leq 150^\circ\text{C}$



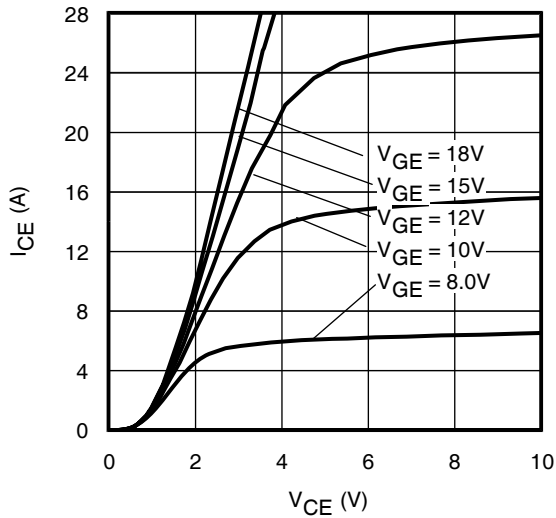
**Fig. 4** - Reverse Bias SOA  
 $T_J = 150^\circ\text{C}$ ;  $V_{CE} = 15\text{V}$



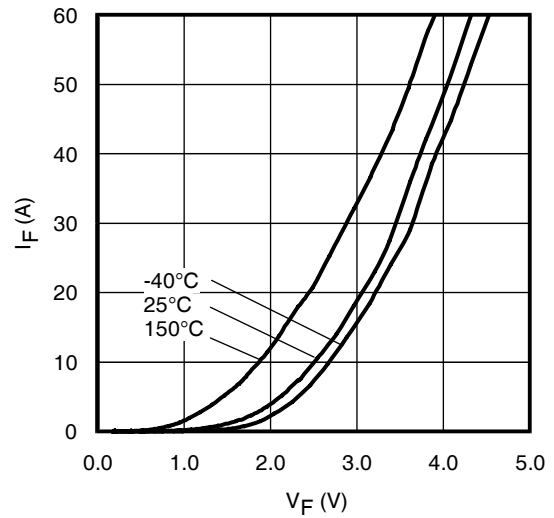
**Fig. 5** - Typ. IGBT Output Characteristics  
 $T_J = -40^\circ\text{C}$ ;  $t_p < 60\mu\text{s}$



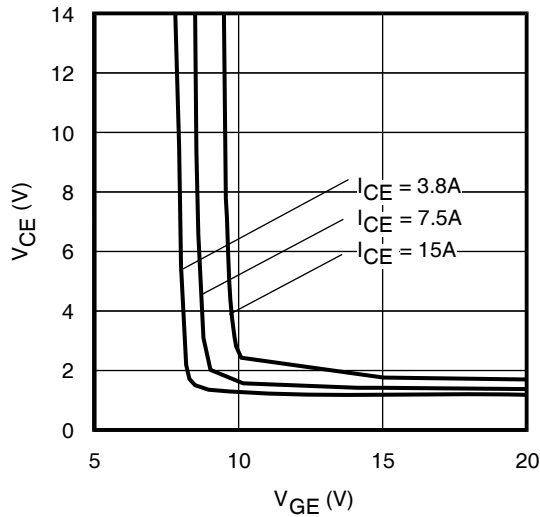
**Fig. 6** - Typ. IGBT Output Characteristics  
 $T_J = 25^\circ\text{C}$ ;  $t_p < 60\mu\text{s}$



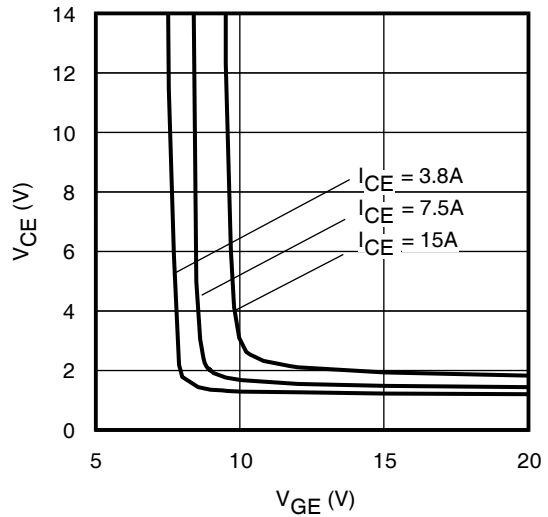
**Fig. 7 - Typ. IGBT Output Characteristics**  
 $T_J = 150^\circ\text{C}$ ;  $t_p < 60\mu\text{s}$



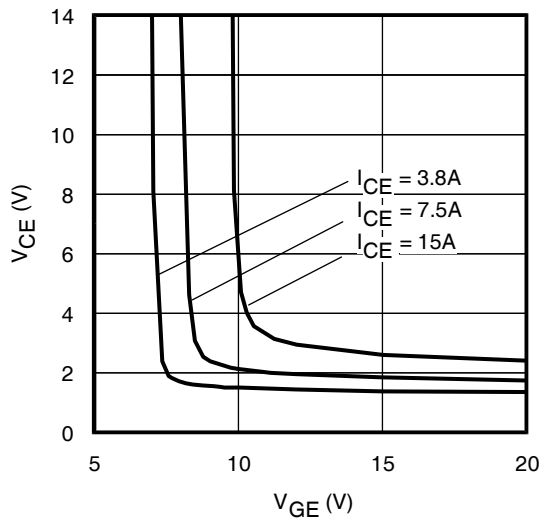
**Fig. 8 - Typ. Diode Forward Characteristics**  
 $t_p < 60\mu\text{s}$



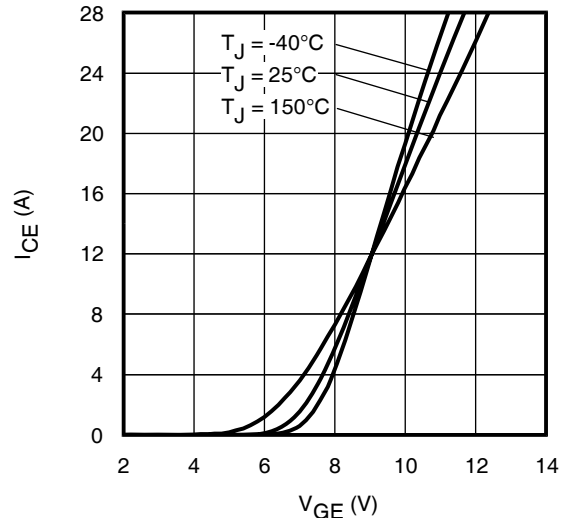
**Fig. 9 - Typical  $V_{CE}$  vs.  $V_{GE}$**   
 $T_J = -40^\circ\text{C}$



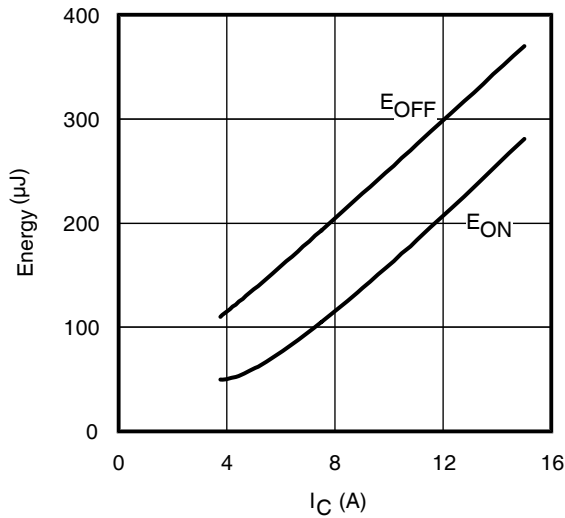
**Fig. 10 - Typical  $V_{CE}$  vs.  $V_{GE}$**   
 $T_J = 25^\circ\text{C}$



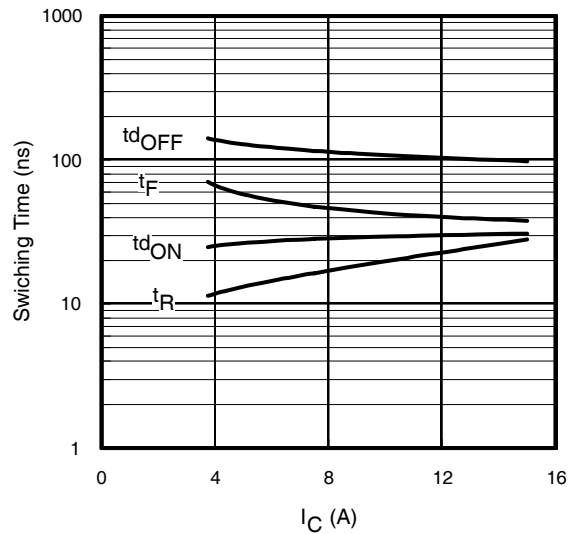
**Fig. 11 - Typical  $V_{CE}$  vs.  $V_{GE}$**   
 $T_J = 150^\circ\text{C}$



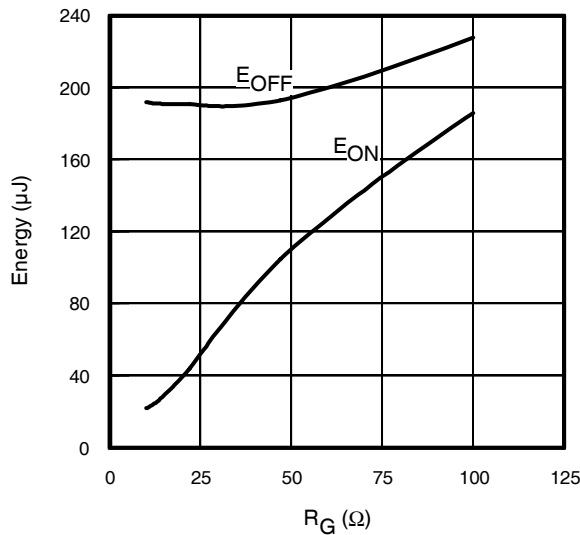
**Fig. 12 - Typ. Transfer Characteristics**  
 $V_{CE} = 50\text{V}$ ;  $t_p < 60\mu\text{s}$



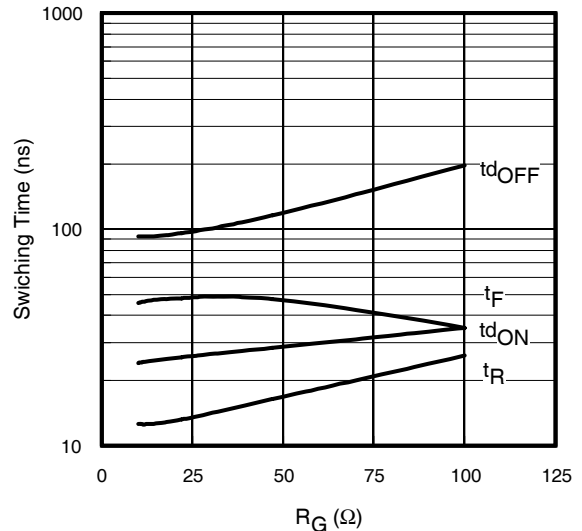
**Fig. 13** - Typ. Energy Loss vs.  $I_C$   
 $T_J = 150^\circ\text{C}$ ;  $L = 1\text{mH}$ ;  $V_{CE} = 400\text{V}$ ;  $R_G = 47\Omega$ ;  $V_{GE} = 15\text{V}$ .



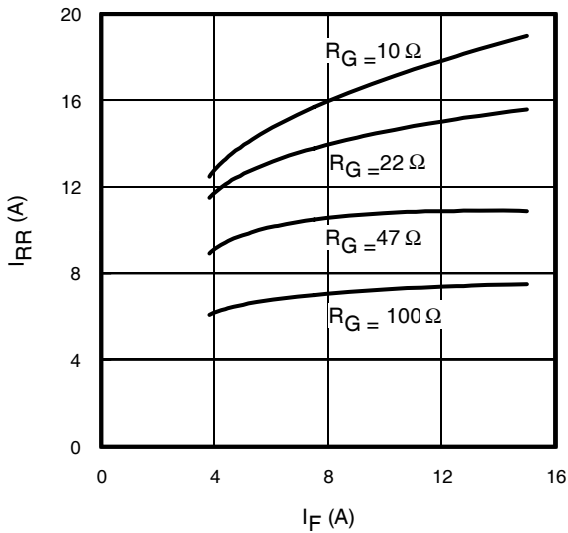
**Fig. 14** - Typ. Switching Time vs.  $I_C$   
 $T_J = 150^\circ\text{C}$ ;  $L = 1\text{mH}$ ;  $V_{CE} = 400\text{V}$   
 $R_G = 47\Omega$ ;  $V_{GE} = 15\text{V}$



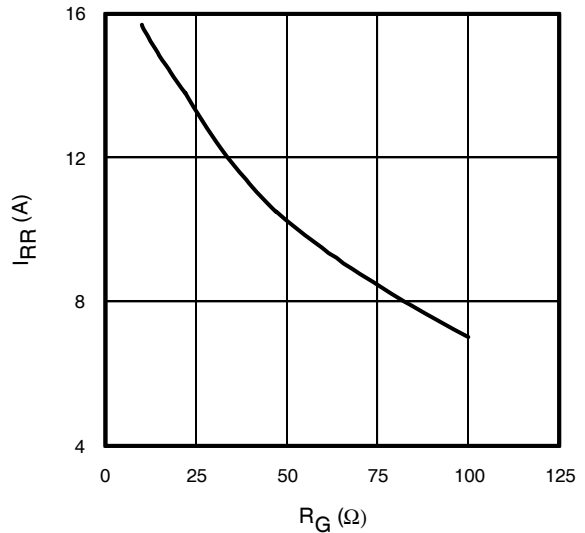
**Fig. 15** - Typ. Energy Loss vs.  $R_G$   
 $T_J = 150^\circ\text{C}$ ;  $L = 1\text{mH}$ ;  $V_{CE} = 400\text{V}$ ;  $I_{CE} = 7.5\text{A}$ ;  $V_{GE} = 15\text{V}$



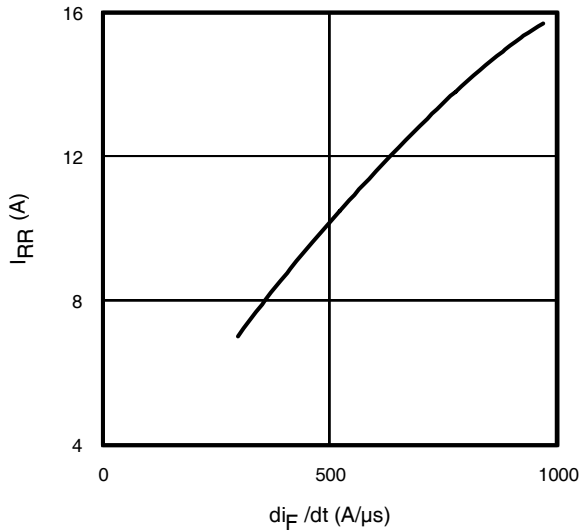
**Fig. 16** - Typ. Switching Time vs.  $R_G$   
 $T_J = 150^\circ\text{C}$ ;  $L = 1\text{mH}$ ;  $V_{CE} = 400\text{V}$   
 $I_{CE} = 7.5\text{A}$ ;  $V_{GE} = 15\text{V}$



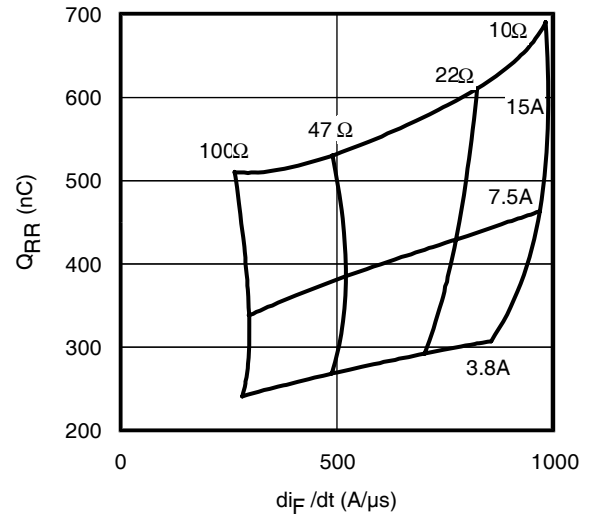
**Fig. 17** - Typical Diode  $I_{RR}$  vs.  $I_F$   
 $T_J = 150^\circ\text{C}$



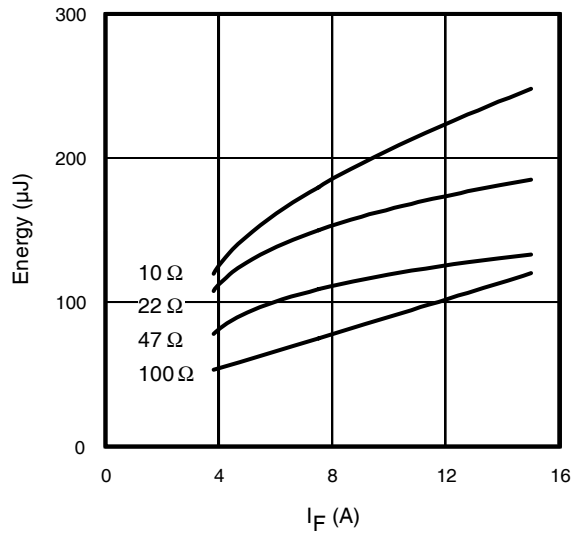
**Fig. 18** - Typical Diode  $I_{RR}$  vs.  $R_G$   
 $T_J = 150^\circ\text{C}$ ;  $I_F = 7.5\text{A}$



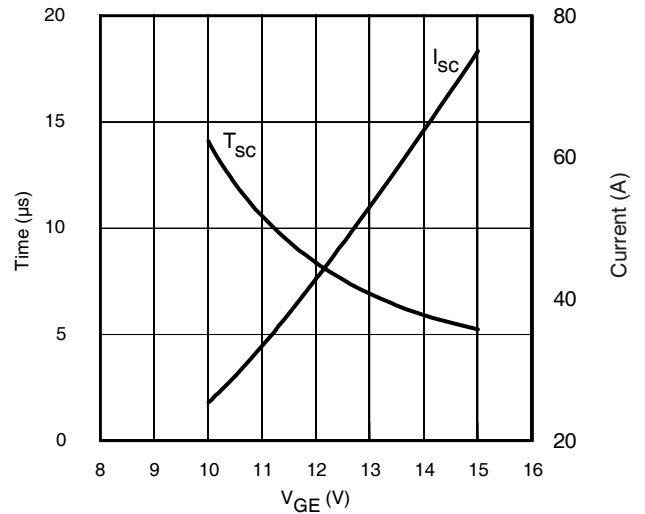
**Fig. 19** - Typical Diode  $I_{RR}$  vs.  $di_F/dt$   
 $V_{CC}=400V$ ;  $V_{GE}=15V$ ;  
 $I_{CE}=7.5A$ ;  $T_J=150^\circ C$



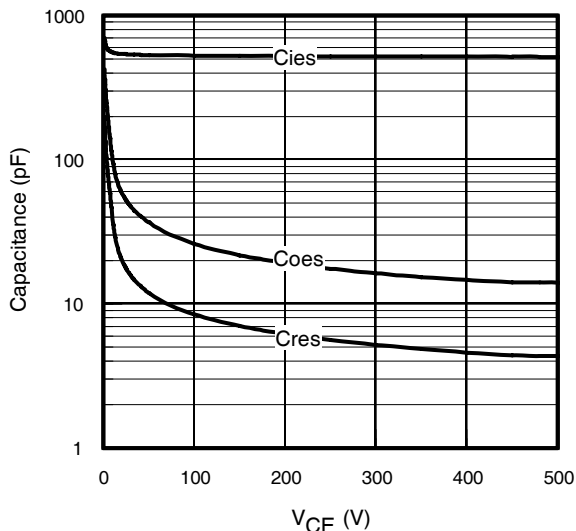
**Fig. 20** - Typical Diode  $Q_{RR}$   
 $V_{CC}=400V$ ;  $V_{GE}=15V$ ;  $T_J=150^\circ C$



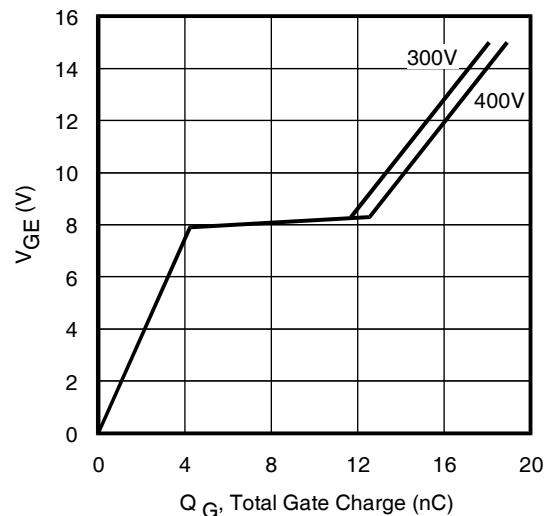
**Fig. 21** - Typical Diode  $E_{RR}$  vs.  $I_F$   
 $T_J=150^\circ C$



**Fig. 22** - Typ.  $V_{GE}$  vs Short Circuit Time  
 $V_{CC}=400V$ ,  $T_C=25^\circ C$



**Fig. 23** - Typ. Capacitance vs.  $V_{CE}$   
 $V_{GE}=0V$ ;  $f=1MHz$



**Fig. 24** - Typical Gate Charge vs.  $V_{GE}$   
 $I_{CE}=7.5A$ ,  $L=600\mu H$

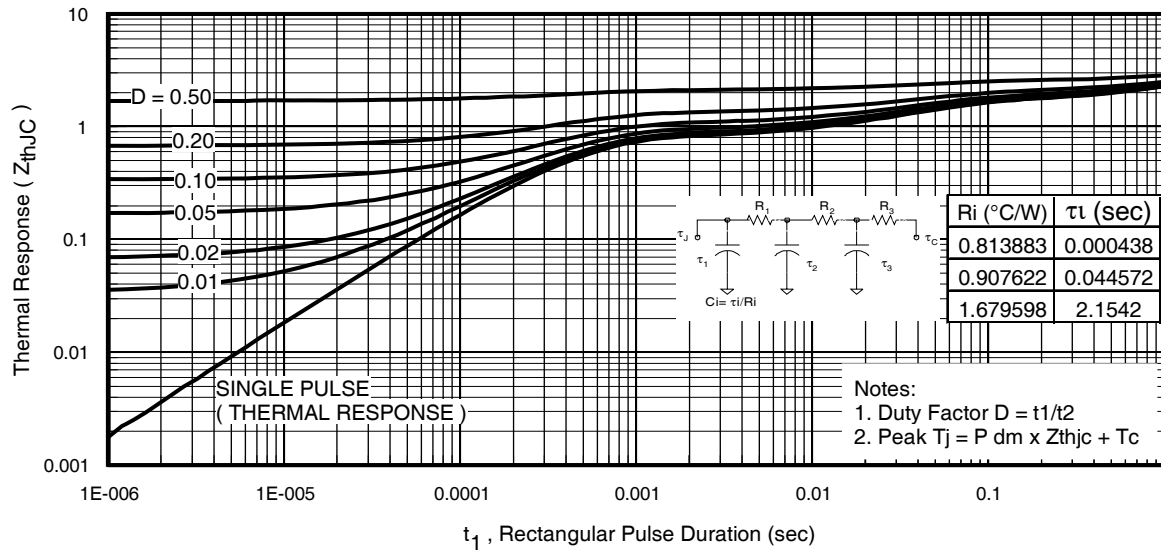


Fig 25. Maximum Transient Thermal Impedance, Junction-to-Case (IGBT)

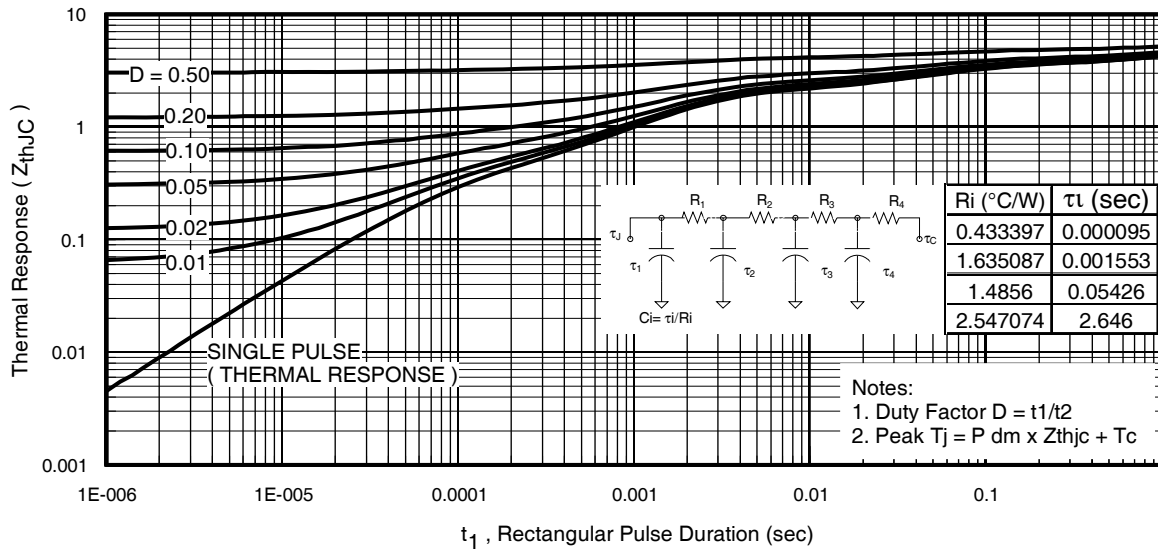
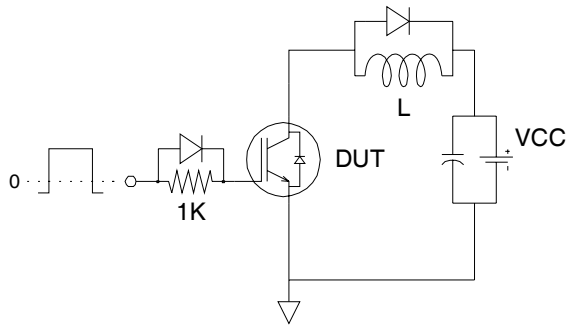
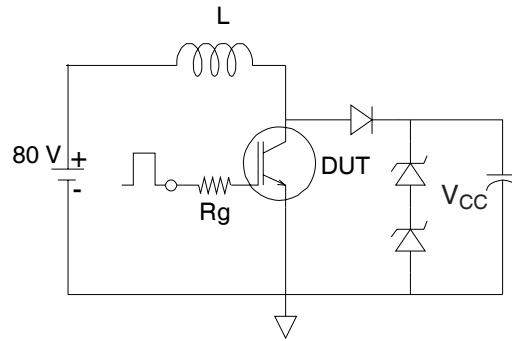


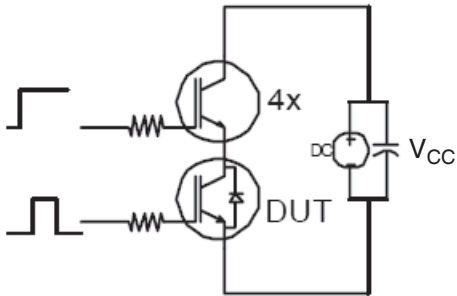
Fig. 26. Maximum Transient Thermal Impedance, Junction-to-Case (DIODE)



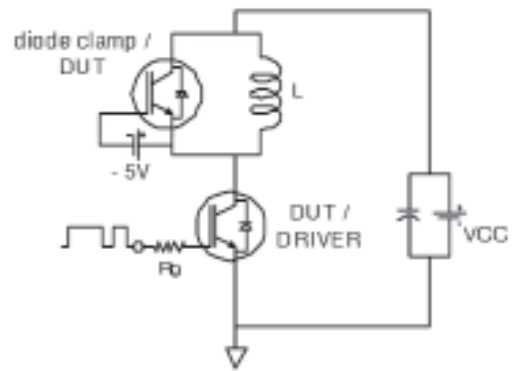
**Fig.C.T.1** - Gate Charge Circuit (turn-off)



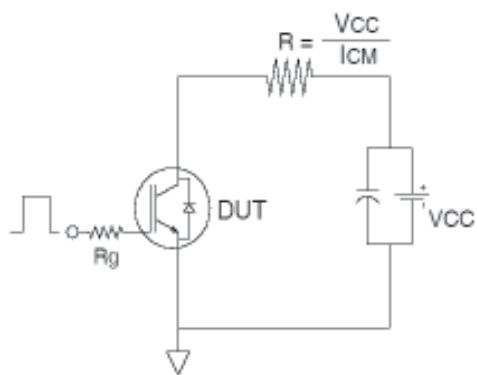
**Fig.C.T.2** - RBSOA Circuit



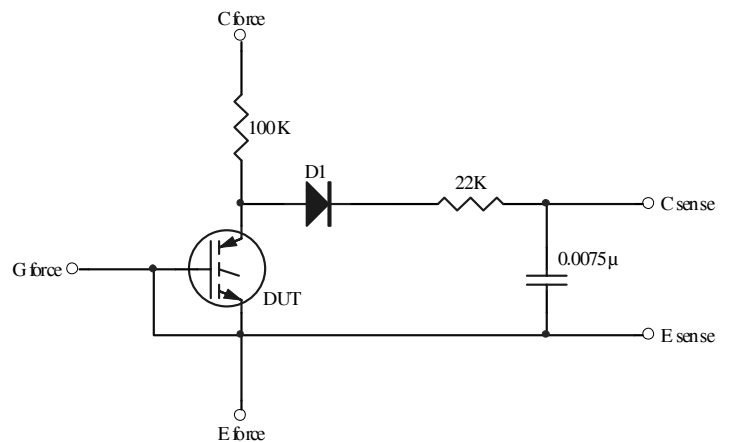
**Fig.C.T.3** - S.C.SOA Circuit



**Fig.C.T.4** - Switching Loss Circuit

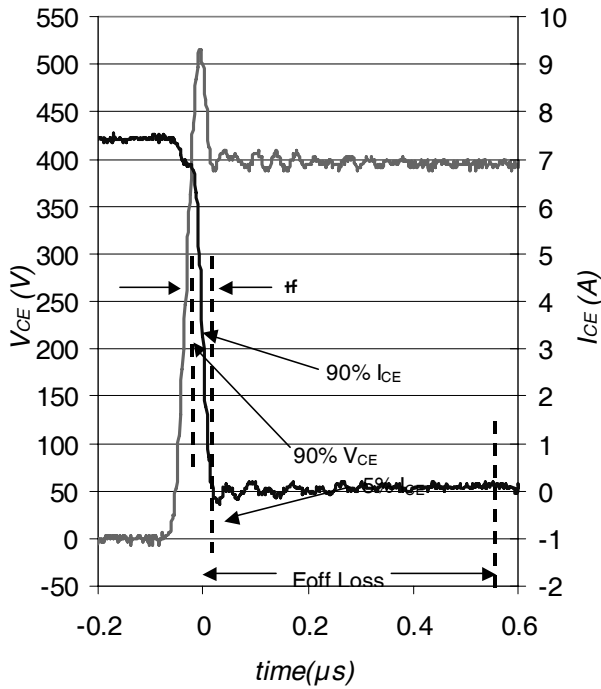


**Fig.C.T.5** - Resistive Load Circuit

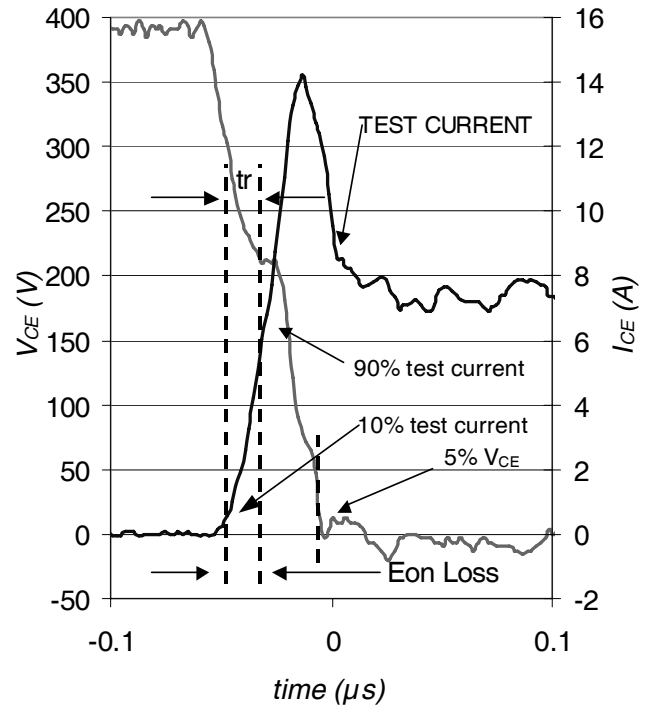


**Fig.C.T.6** - Typical Filter Circuit for  $V_{(BR)CES}$  Measurement

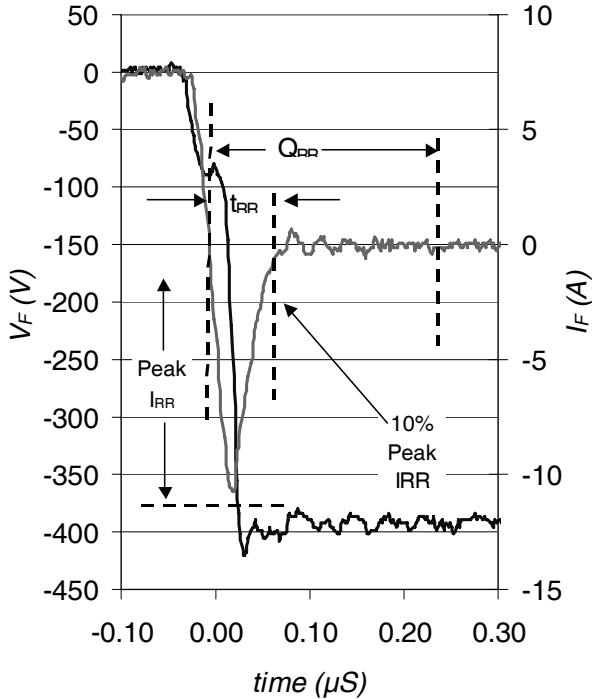




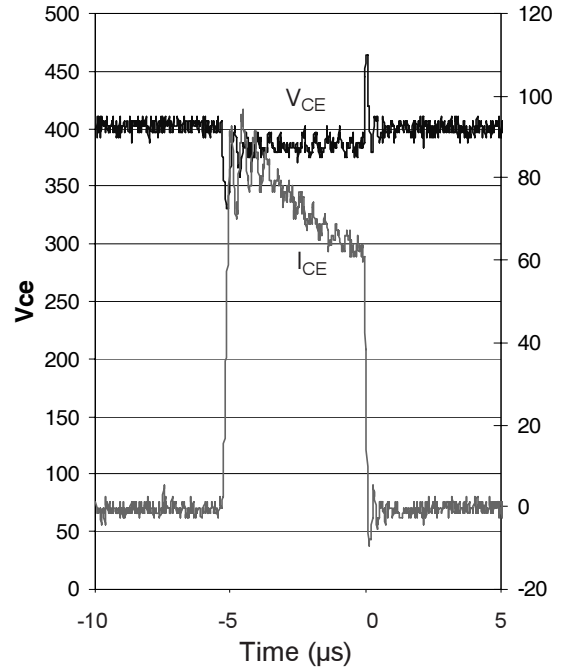
**Fig. WF1** - Typ. Turn-off Loss Waveform  
@  $T_J = 150^\circ\text{C}$  using Fig. CT.4



**Fig. WF2** - Typ. Turn-on Loss Waveform  
@  $T_J = 150^\circ\text{C}$  using Fig. CT.4



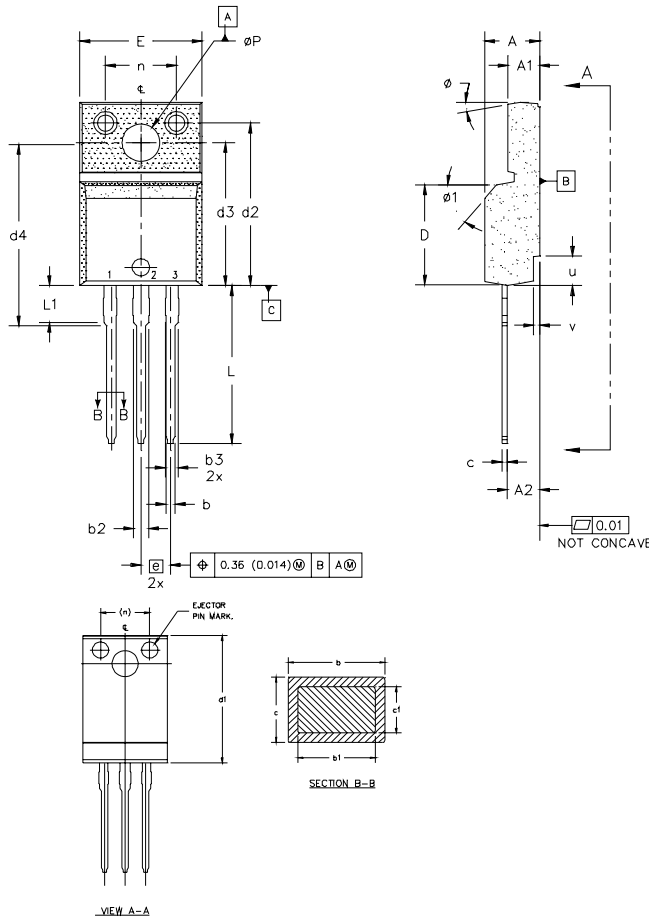
**WF.3-** Typ. Reverse Recovery Waveform  
@  $T_J = 150^\circ\text{C}$  using CT.4



**WF.4-** Typ. Short Circuit Waveform  
@  $T_J = 25^\circ\text{C}$  using CT.3

## TO-220 Full-Pak Package Outline

Dimensions are shown in millimeters (inches)



- NOTES:
- 1.0 DIMENSIONING AND TOLERANCING PER ASME Y14.5 M- 1994.
  - 2.0 DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].
  - 3.0 LEAD DIMENSION AND FINISH UNCONTROLLED IN L1.
  - 4.0 DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED 0.008" (0.127) PER SIDE, THESE DIMENSIONS ARE MEASURED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.
  - 5.0 DIMENSION b1 APPLY TO BASE METAL ONLY.
  - 6.0 STEP OPTIONAL ON PLASTIC BODY DEFINED BY DIMENSIONS u & v.
  - 7.0 CONTROLLING DIMENSION : INCHES.

SYMBOL	DIMENSIONS				NOTES
	MILLIMETERS		INCHES		
	MIN.	MAX.	MIN.	MAX.	
A	4.57	4.83	0.180	0.190	5
A1	2.57	2.83	0.101	0.114	
A2	2.51	2.85	0.099	0.112	
b	0.622	0.89	0.024	0.035	
b1	0.622	0.838	0.024	0.033	
b2	1.229	1.400	0.048	0.055	
b3	1.229	1.400	0.048	0.055	
c	0.440	0.629	0.017	0.025	4
c1	0.440	0.584	0.017	0.023	
D	8.65	9.80	0.341	0.386	
d1	15.80	16.12	0.622	0.635	
d2	13.97	14.22	0.550	0.560	
d3	12.30	12.92	0.484	0.509	
d4	8.64	9.91	0.340	0.390	
E	10.36	10.63	0.408	0.419	4
e	2.54 BSC		0.100 BSC		
L	13.20	13.73	0.520	0.541	3
L1	3.10	3.50	0.122	0.138	
n	6.05	6.15	0.238	0.242	6
phi P	3.05	3.45	0.120	0.136	
u	2.40	2.50	0.094	0.098	6
v	0.40	0.50	0.016	0.020	
phi	3°	7°	3°	7°	
phi 1		45°		45°	

**LEAD ASSIGNMENTS**

**HEXFET**

- 1.- GATE
- 2.- DRAIN
- 3.- SOURCE

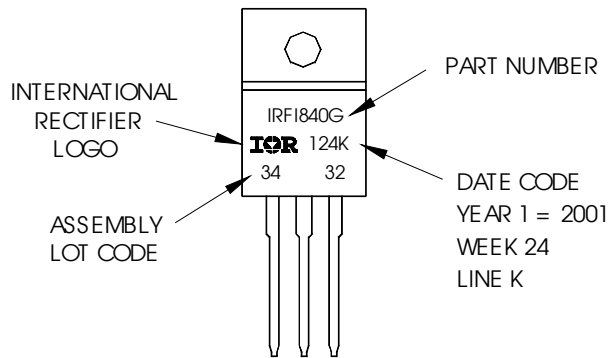
**IGBTs, CoPACK**

- 1.- GATE
- 2.- COLLECTOR
- 3.- EMITTER

## TO-220 Full-Pak Part Marking Information

EXAMPLE: THIS IS AN IRF1840G  
WITH ASSEMBLY  
LOT CODE 3432  
ASSEMBLED ON WW 24, 2001  
IN THE ASSEMBLY LINE "K"

Note: "P" in assembly line position  
indicates "Lead-Free"



TO-220 Full-Pak package is not recommended for Surface Mount Application.

Note: For the most current drawing please refer to IR website at: <http://www.irf.com/package/>

Data and specifications subject to change without notice.  
This product has been designed and qualified for Industrial market.  
Qualification Standards can be found on IR's Web site.